

<b>Notice of References Cited</b>	Application/Control No. 10/559,984		Applicant(s)/Patent Under Reexamination ANDERSON, MARK	
	Examiner Ahshik Kim		Art Unit 2876	Page 1 of 1

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*	B	US-7,155,199	12-2006	Zalewski et al.	455/403
*	C	US-6,745,944	06-2004	Dell, Jason S.	235/492
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	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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